

<b>Notice of References Cited</b>	Application/Control No. 10/017,027	Applicant(s)/Patent Under Reexamination IIZUKA, TOSHIAKI	
	Examiner Jonathan Ouellette	Art Unit 3629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,216,113	04-2001	Aikens et al.	705/34
*	B	US-6,434,343	08-2002	Kobayashi et al.	399/8
*	C	US-6,772,191	08-2004	Kurosawa et al.	709/203
*	D	US-6,249,836	06-2001	Downs et al.	710/268
*	E	US-6,996,555	02-2006	Muto et al.	707/3
*	F	US-6,947,995	09-2005	Chang et al.	709/231
*	G	US-6,516,304	02-2003	Yoshimura, Miki	705/52
*	H	US-2002/0112171	08-2002	Ginter et al.	713/185
*	I	US-2002/0107817	08-2002	NAKAJIMA, NOBUYUKI	705/400
*	J	US-2002/0069176	06-2002	Newman, Daniel	705/53
*	K	US-2001/0038462	11-2001	Teeuwen et al.	358/1.15
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.